

TITLE: SYSTEM AND METHOD FOR MEASURING TRANSISTOR LEAKAGE CURRENT WITH A RING OSCILLATOR WITH BACKBIAS CONTROLS

Inventor (s): Shingo Suzuki

Attorney Docket #: TRAN-P140.CIP

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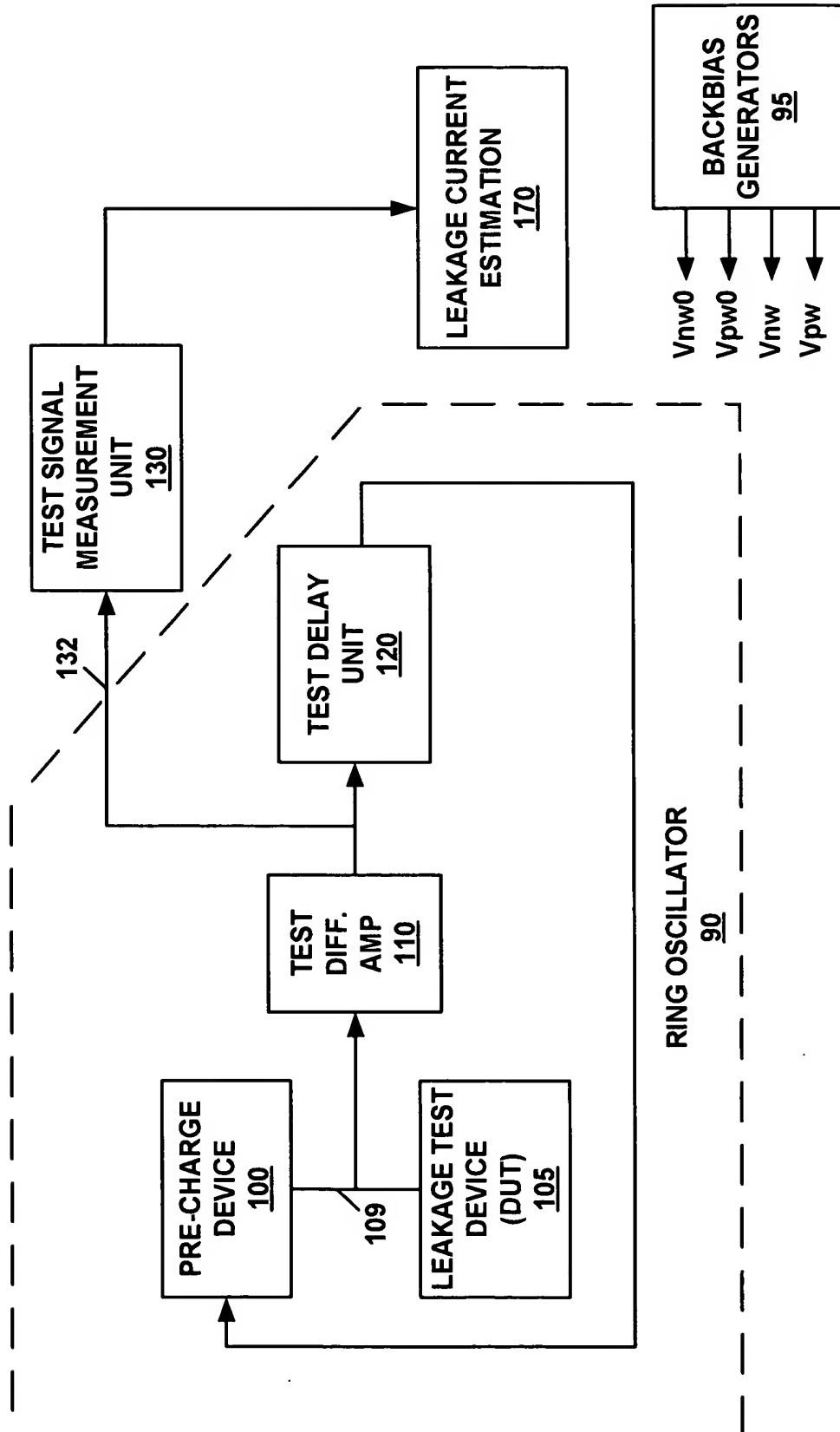
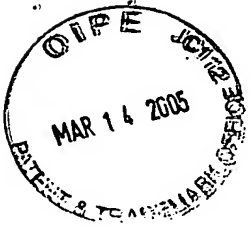
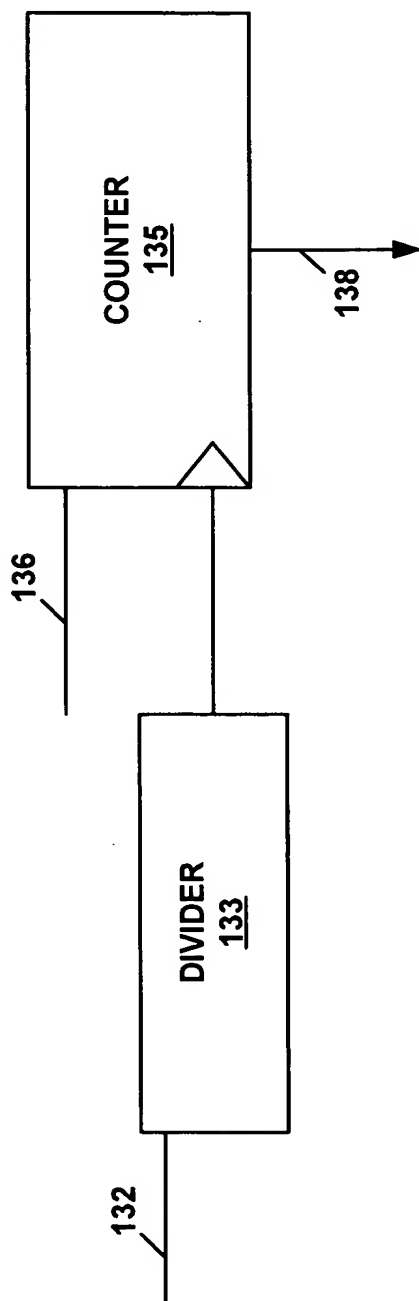


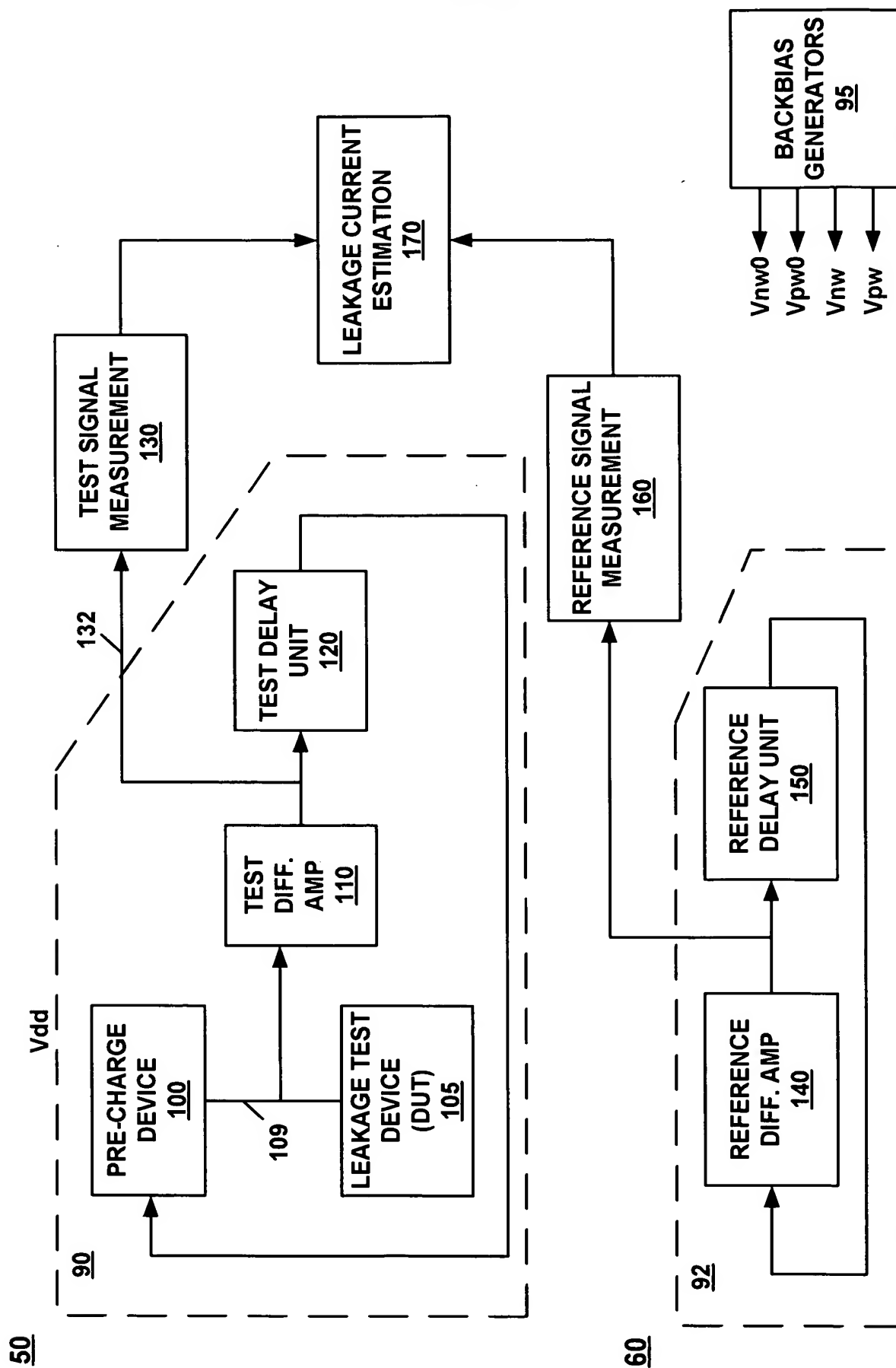
FIGURE 1



**FIGURE 2**









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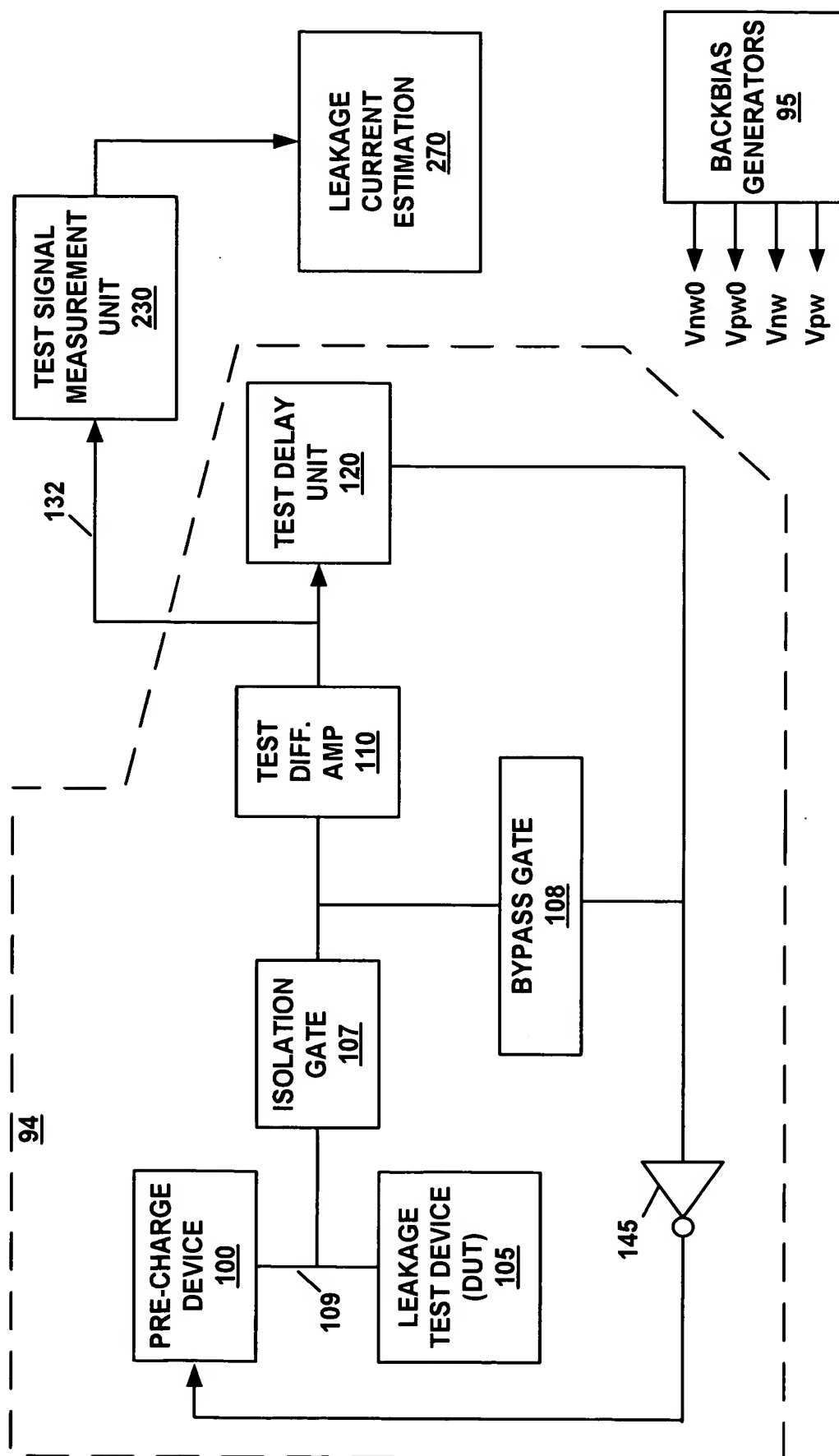
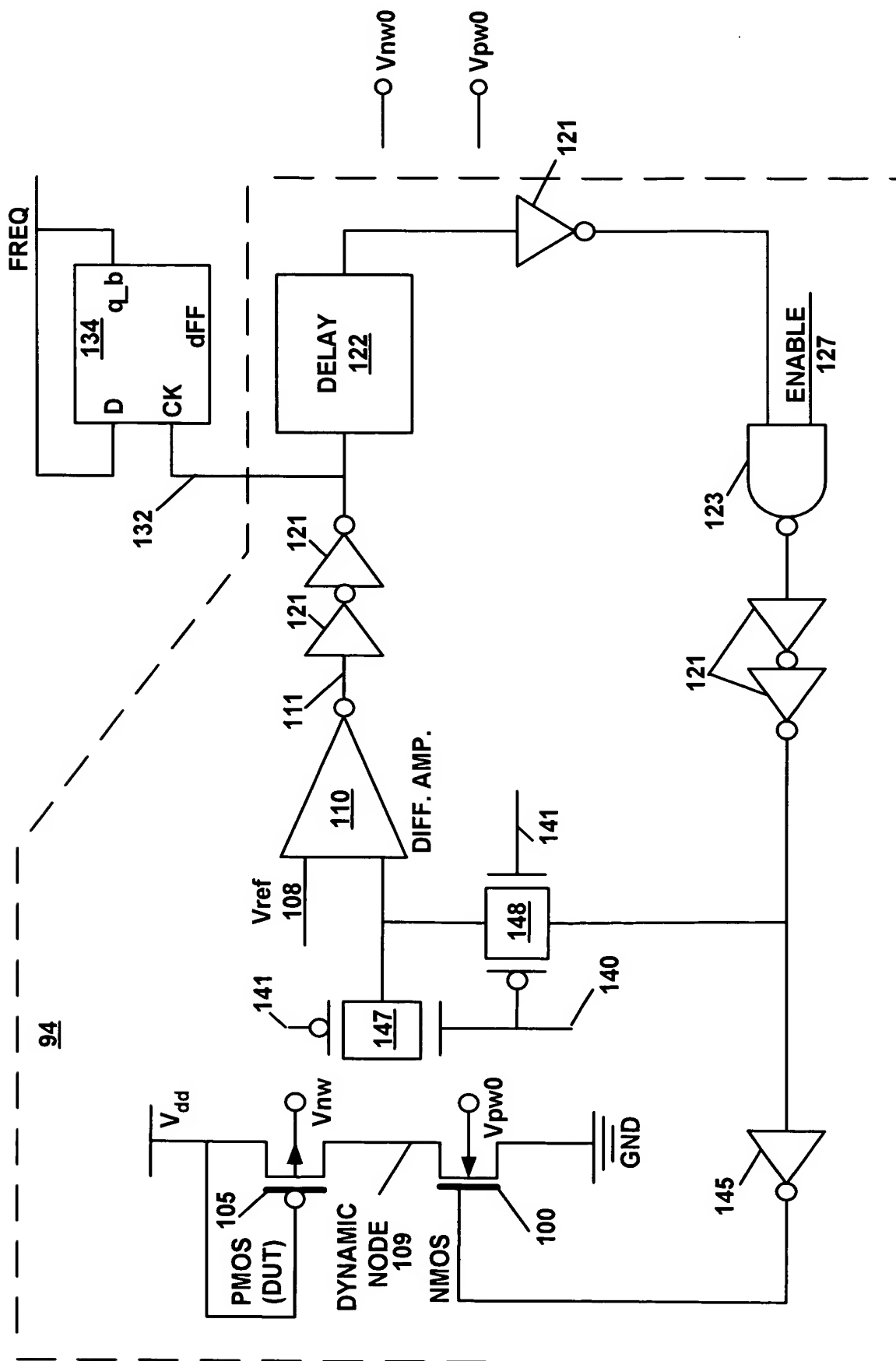


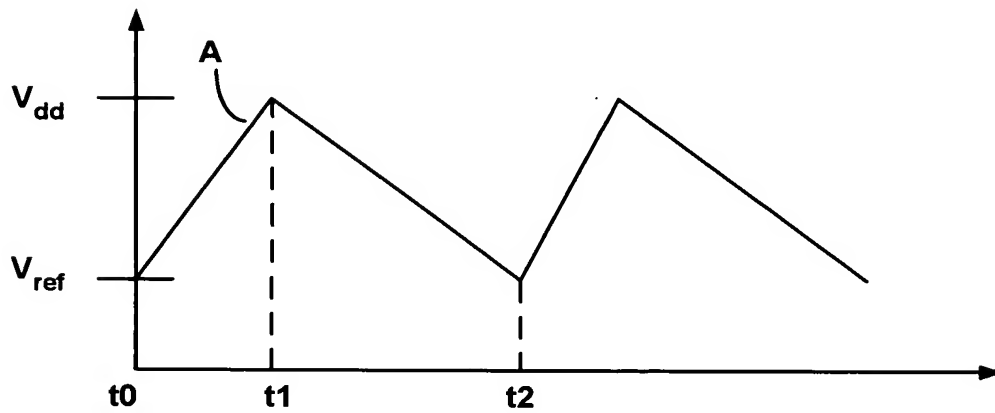
FIGURE 7



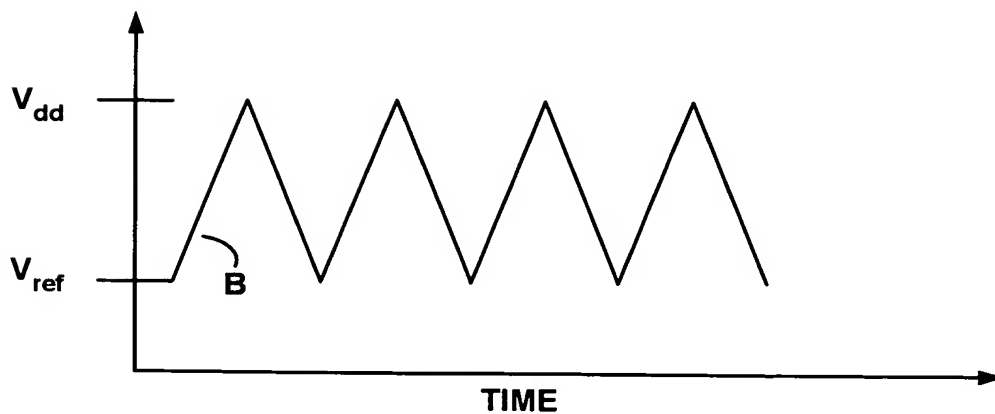




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**FIGURE 10A**



**FIGURE 10B**

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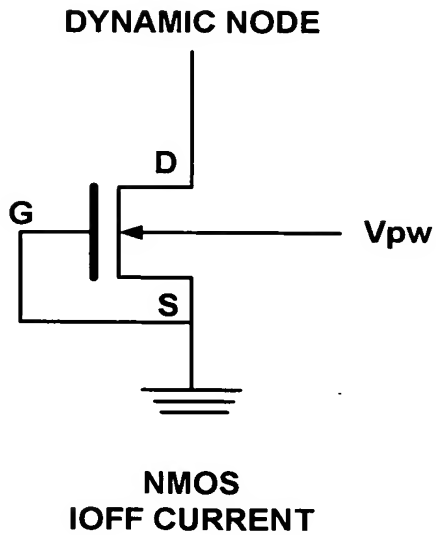


FIGURE 11

205

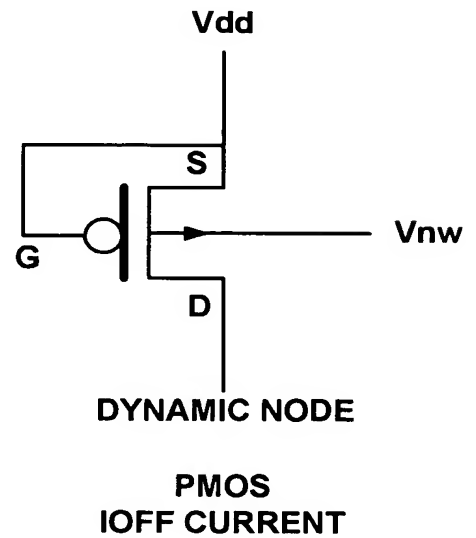


FIGURE 12

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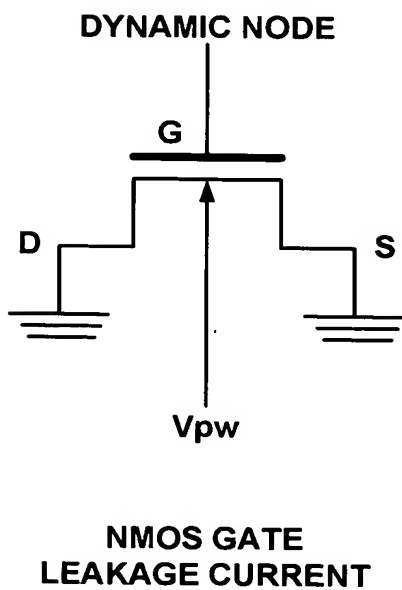


FIGURE 13

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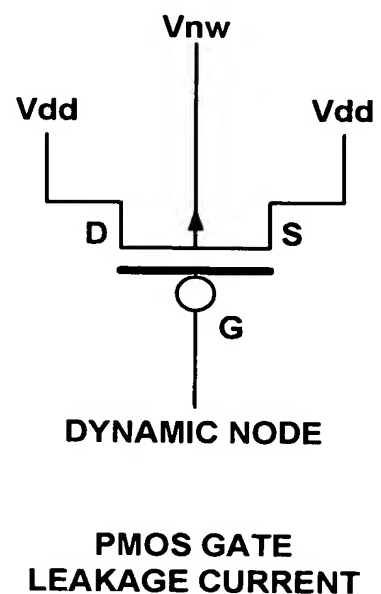
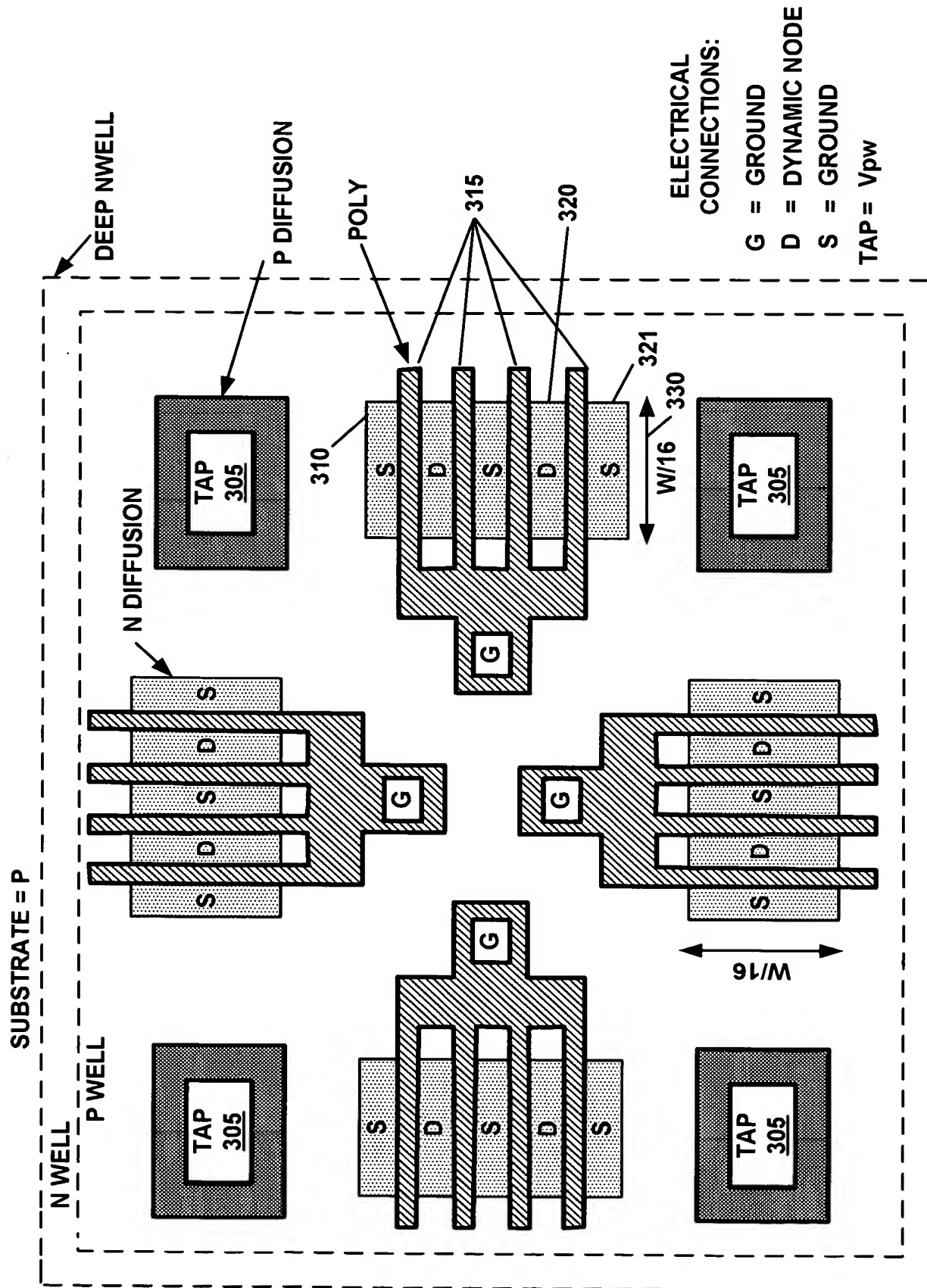
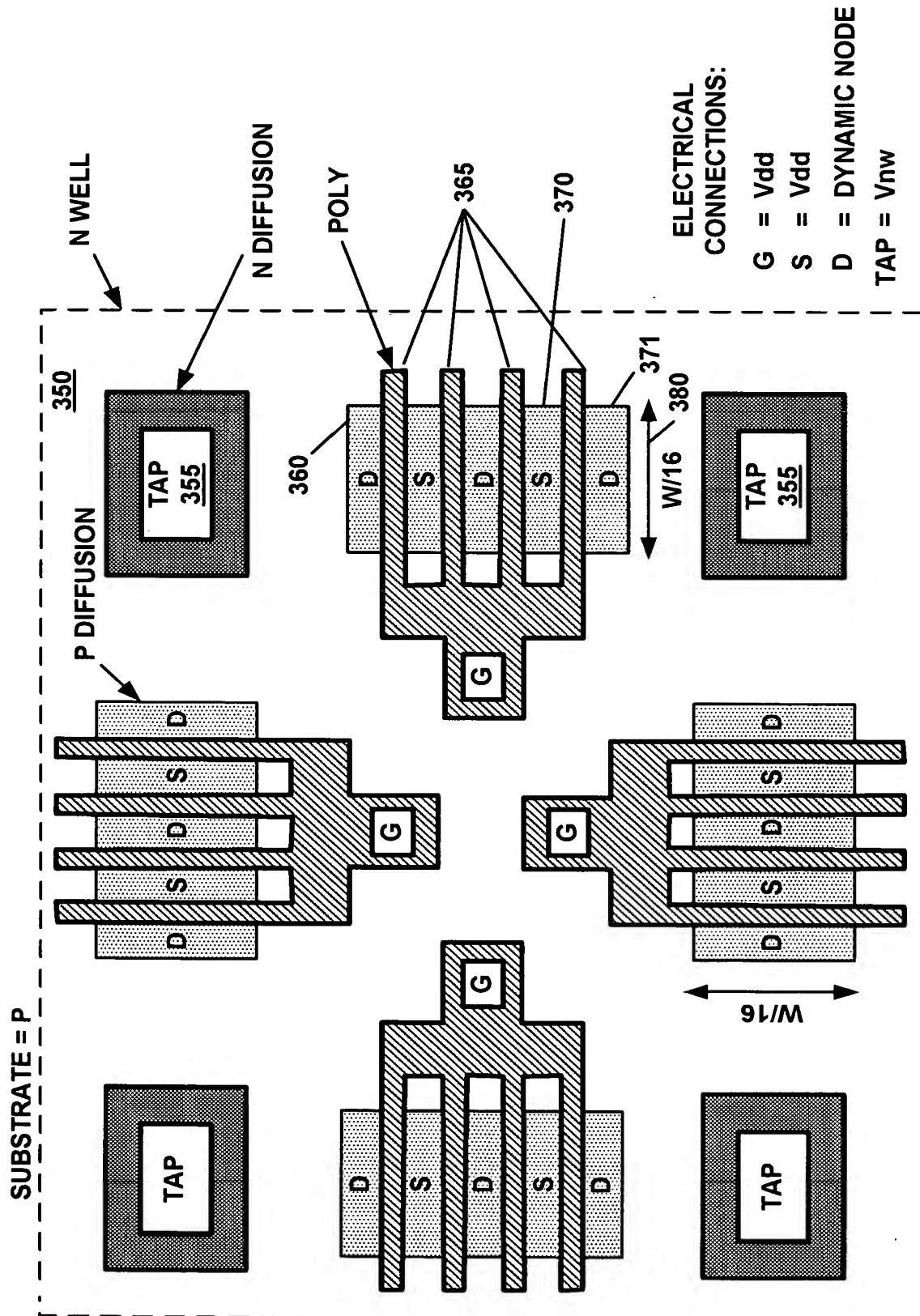


FIGURE 14

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# FIGURE 15



# FIGURE 16

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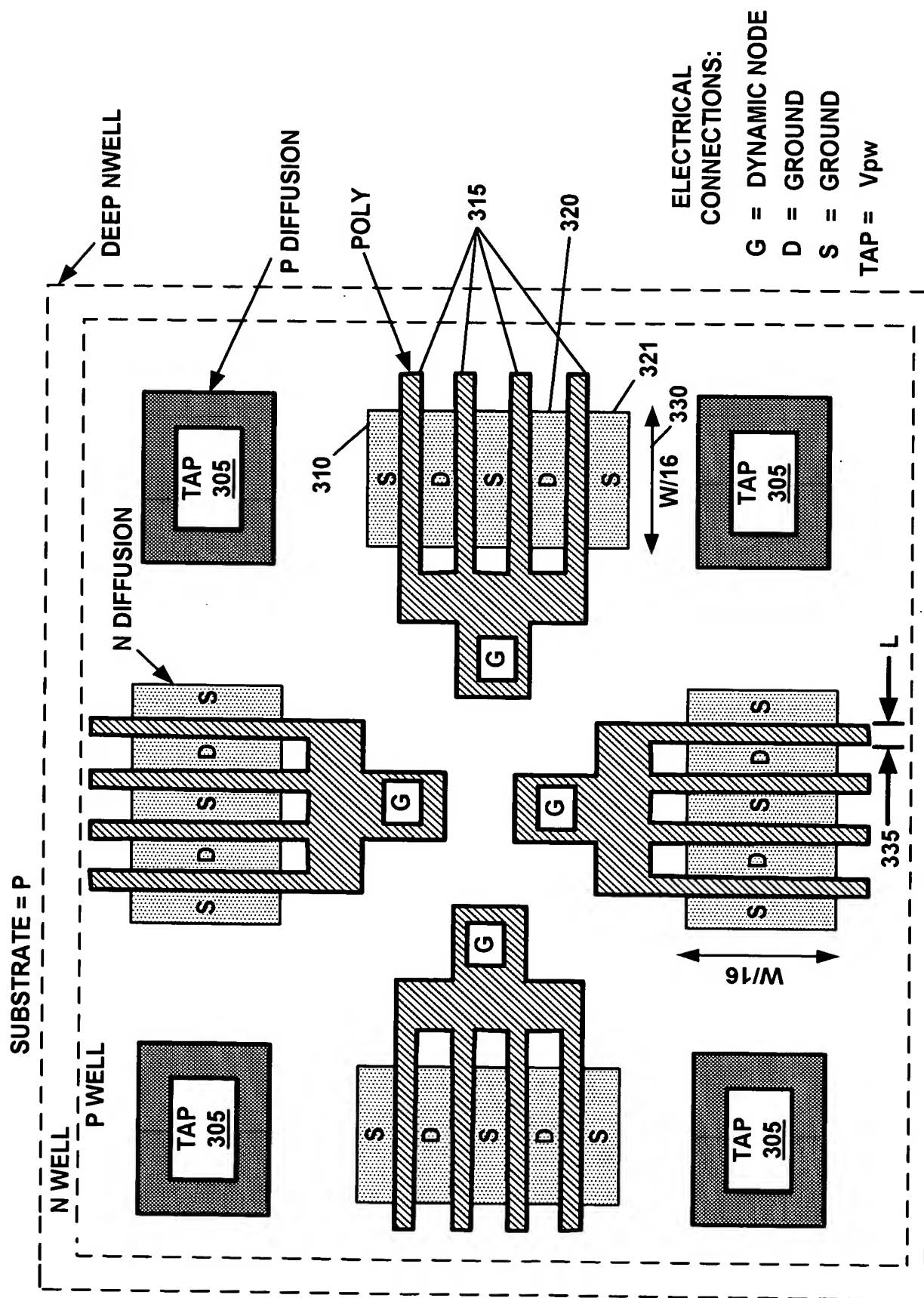


FIGURE 17



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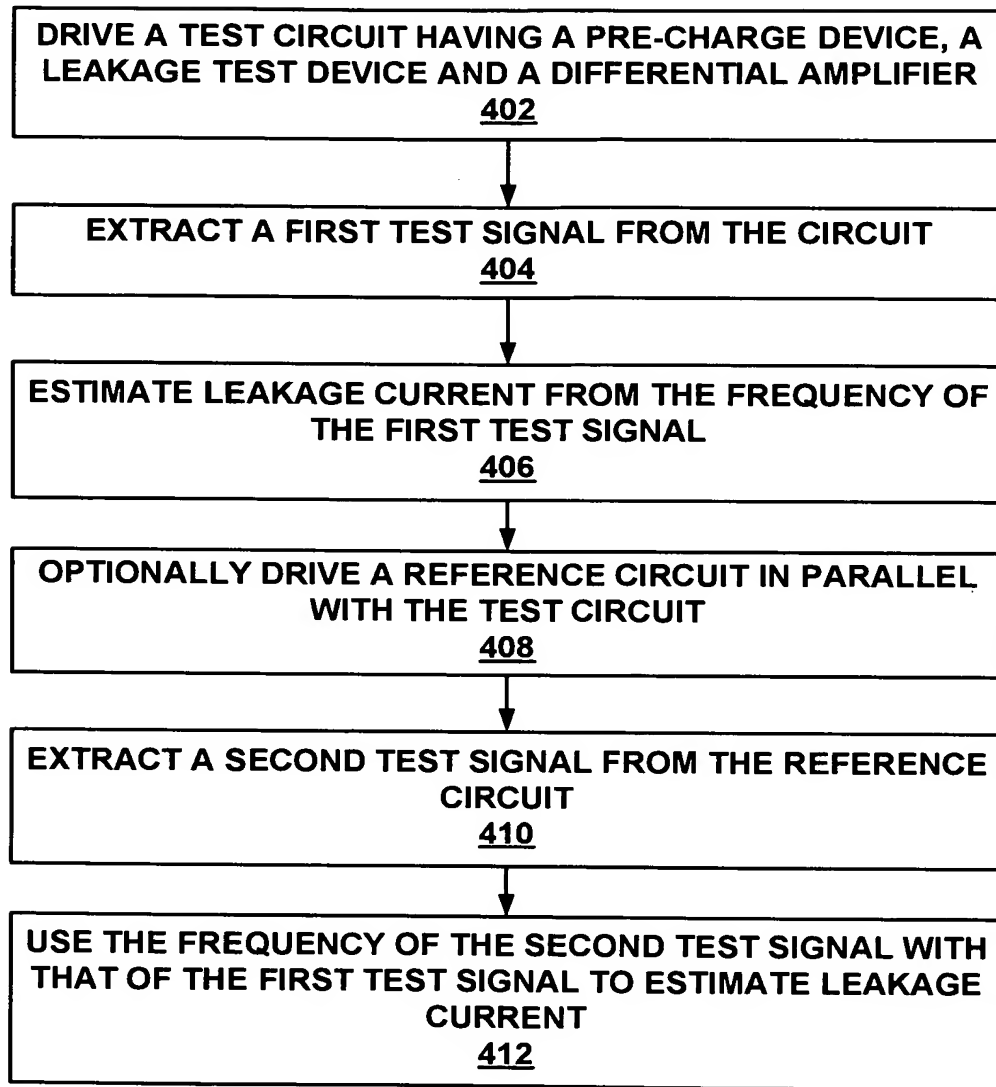


FIGURE 19